

## 30V N-Channel Enhancement Mode MOSFET

### Description

The AP80N03BDF uses advanced **APM-SGT V** technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

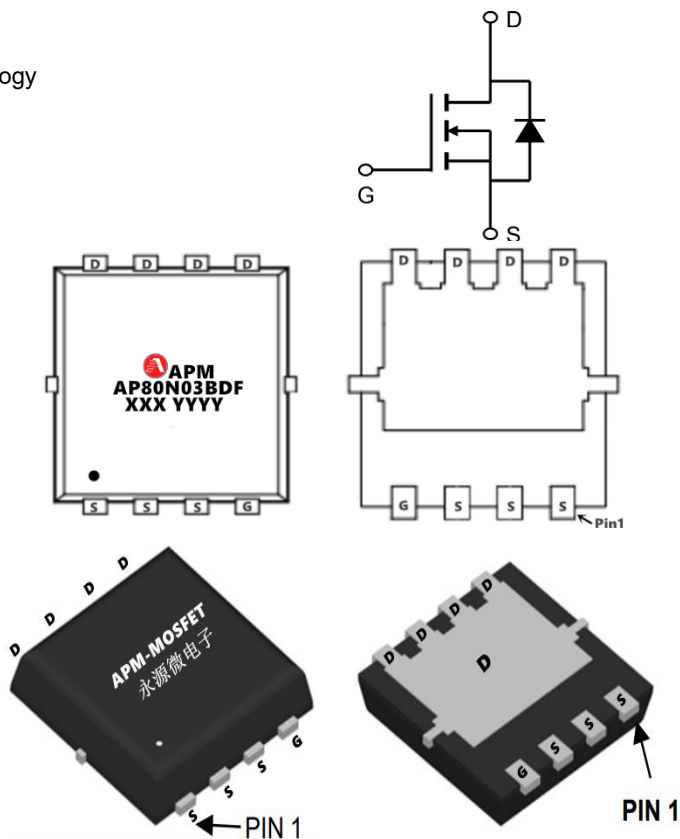
$V_{DS} = 30V$   $I_D = 80A$

$R_{DS(ON)} < 3.8m\Omega$  @  $V_{GS}=10V$  (Type: **3.0mΩ**)

### Application

Buck

Boost



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP80N03BDF	PDFN3*3-8L	AP80N03BDF XXX YYYY	5000

### Absolute Maximum Ratings ( $T_C=25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Max.	Units
$V_{DSS}$	Drain-Source Voltage	30	V
$V_{GSS}$	Gate-Source Voltage	$\pm 20$	V
$I_{D@TC=25^{\circ}C}$	Continuous Drain Current, $V_{GS} @ 10V$	80	A
$I_{D@TC=100^{\circ}C}$	Continuous Drain Current, $V_{GS} @ 10V$	54	A
$I_{DM}$	Pulsed Drain Current	344	A
$E_{AS}$	Single Pulsed Avalanche Energy	45	mJ
$I_{AS}$	Avalanche Current	25	A
$P_{D@TC=25^{\circ}C}$	Power Dissipation	43.1	W
$T_J$ TSTG	Operating Junction Temperature Range	-55 to 150	$^{\circ}C$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient <sup>1</sup>	25	$^{\circ}C/W$
$R_{\theta JC}$	Thermal Resistance, Junction to Case	2.9	$^{\circ}C/W$

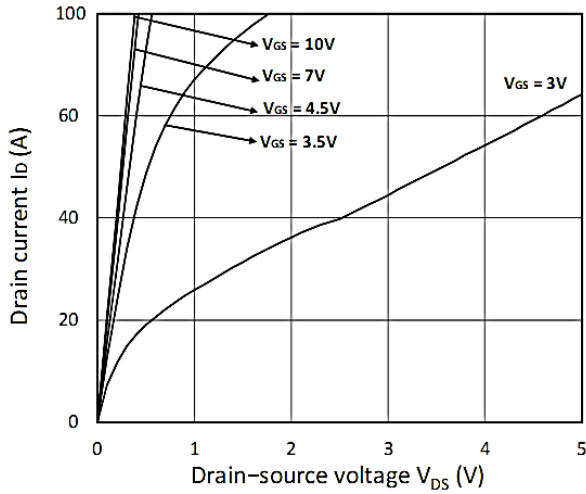
**30V N-Channel Enhancement Mode MOSFET**
**Electrical Characteristics ( $T_J=25^{\circ}\text{C}$ , unless otherwise noted)**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	30	-	-	V
IGSS	Gate-body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	$\pm 100$	nA
IDSS	Zero Gate Voltage Drain Current $T_J=25^{\circ}\text{C}$	$V_{DS} = 30V, V_{GS} = 0V$	-	-	1	$\mu A$
	Zero Gate Voltage Drain Current $T_J=100^{\circ}\text{C}$		-	-	100	
VGS(th)	Gate-Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.2	1.6	2.5	V
RDS(on)	Drain-Source On-Resistance <sup>4</sup>	$V_{GS} = 10V, I_D = 20A$	-	3.0	3.8	m $\Omega$
		$V_{GS} = 4.5V, I_D = 10A$	-	4.5	6.0	
gfs	Forward Transconductance <sup>4</sup>	$V_{DS} = 10V, I_D = 20A$	-	70	-	S
Ciss	Input Capacitance	$V_{DS} = 15V, V_{GS} = 0V, f = 1MHz$	-	1065	-	pF
Coss	Output Capacitance		-	428	-	
Crss	Reverse Transfer Capacitance		-	35	-	
Rg	Gate Resistance	$f = 1MHz$	-	1.2	-	$\Omega$
Qg	Total Gate Charge	$V_{GS} = 10V, V_{DS} = 15V, I_D = 20A$	-	18	-	nC
Qgs	Gate-Source Charge		-	3.2	-	
Qgd	Gate-Drain Charge		-	2.5	-	
td(on)	Turn-On Delay Time	$V_{GS} = 10V, V_{DD} = 15V, R_G = 3\Omega, I_D = 20A$	-	6.1	-	ns
tr	Rise Time		-	4.0	-	
td(off)	Turn-Off Delay Time		-	16.9	-	
tf	Fall Time		-	4.4	-	
trr	Body Diode Reverse Recovery Time	$I_F = 20A, dI/dt = 100A/\mu s$	-	35.6	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	10.8	-	nC
VSD	Diode Forward Voltage <sup>4</sup>	$I_S = 20A, V_{GS} = 0V$	-	-	1.2	V
IS	Continuous Source Current	$T_C = 25^{\circ}\text{C}$	-	-	100	A

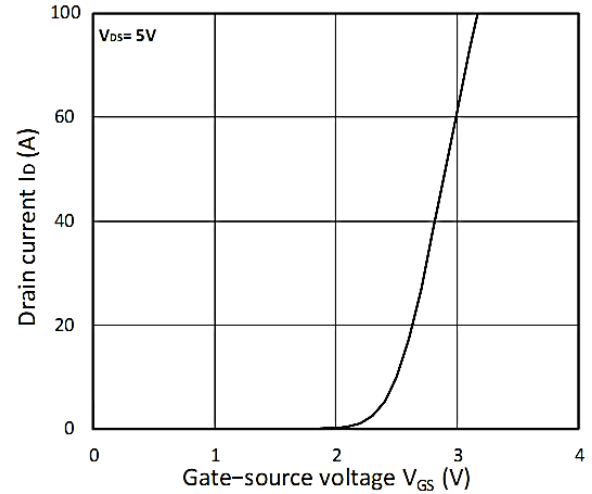
**Note :**

- 1、The data tested by surface mounted on a 1 inch 2 FR-4 board with 20Z copper.
- 2、The data tested by pulsed , pulse width  $\leq 300\mu s$  , duty cycle  $\leq 2\%$
- 3、The EAS data shows Max. rating . The test condition is  $V_{DD} = 25V, V_{GS} = 10V, L = 0.1mH, I_{AS} = 25A$
- 4、The power dissipation is limited by  $150^{\circ}\text{C}$  junction temperature
- 5、The data is theoretically the same as  $I_D$  and  $I_{DM}$  , in real applications , should be limited by total power dissipation.

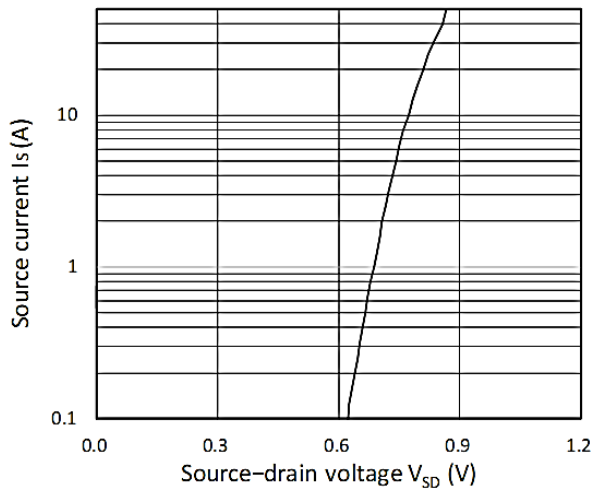
**Typical Characteristics**



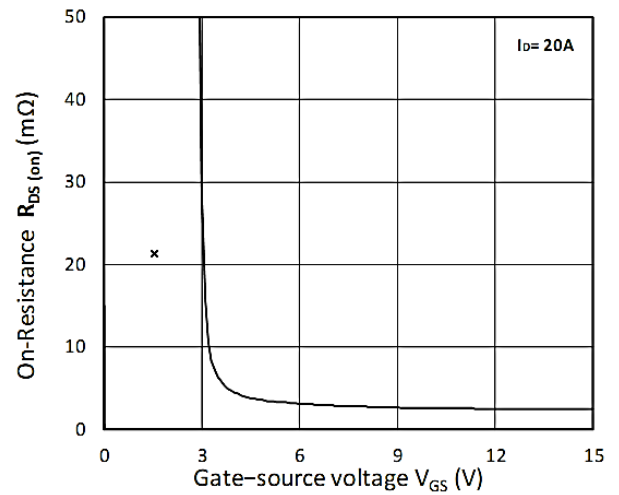
**Figure 1. Output Characteristics**



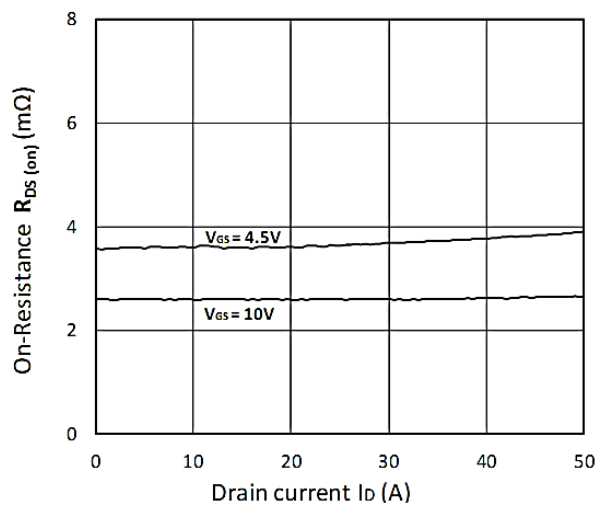
**Figure 2. Transfer Characteristics**



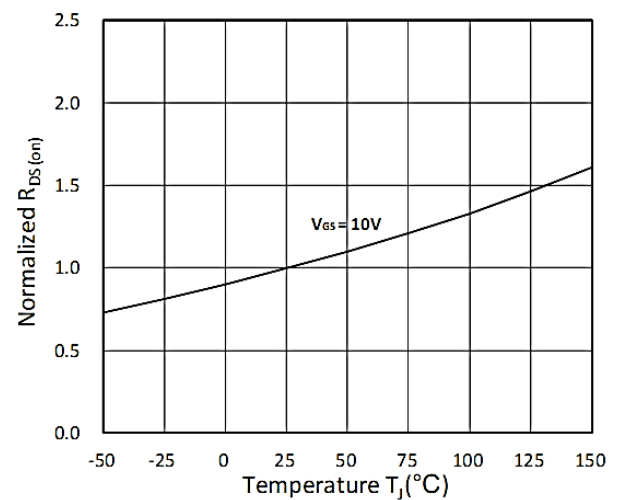
**Figure 3. Forward Characteristics of Reverse**



**Figure 4. R\_DS(ON) vs. V\_GS**

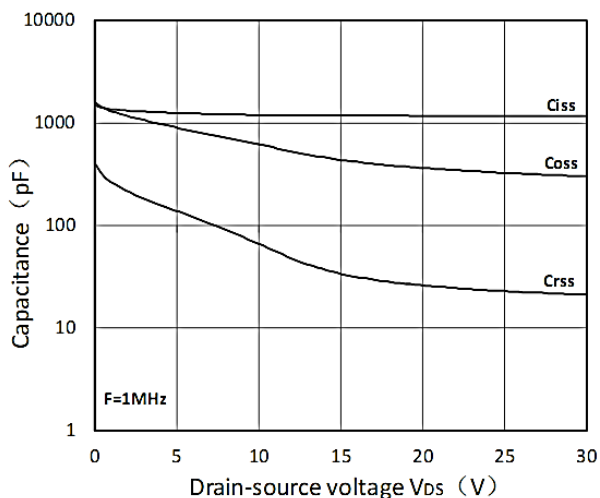


**Figure 5. R\_DS(ON) vs. I\_D**

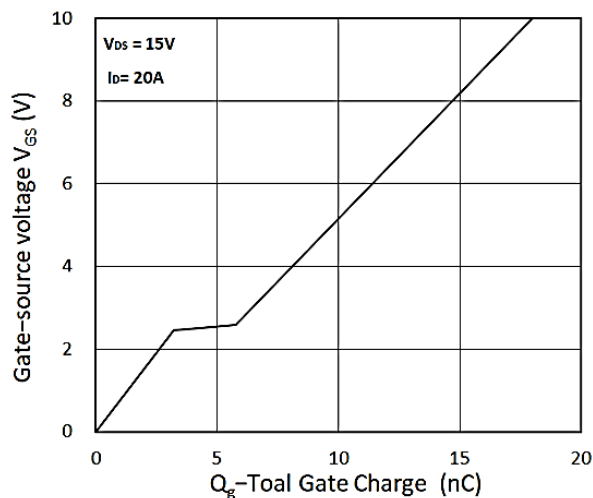


**Figure 6. Normalized R\_DS(on) vs. Temperature**

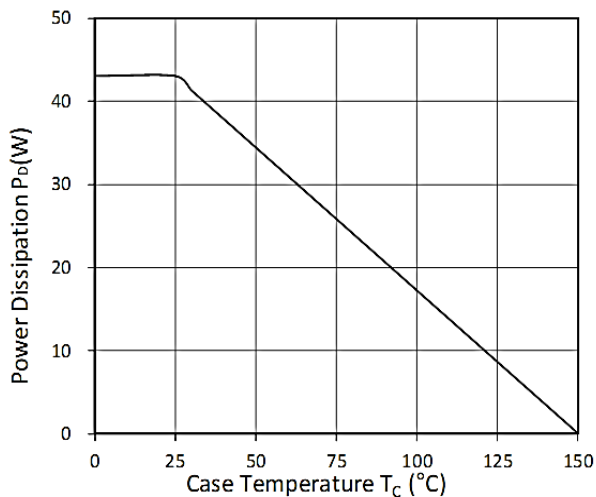
**30V N-Channel Enhancement Mode MOSFET**



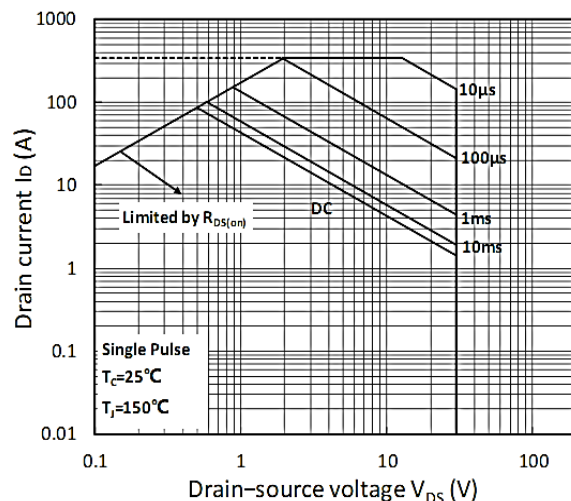
**Figure 7. Capacitance Characteristics**



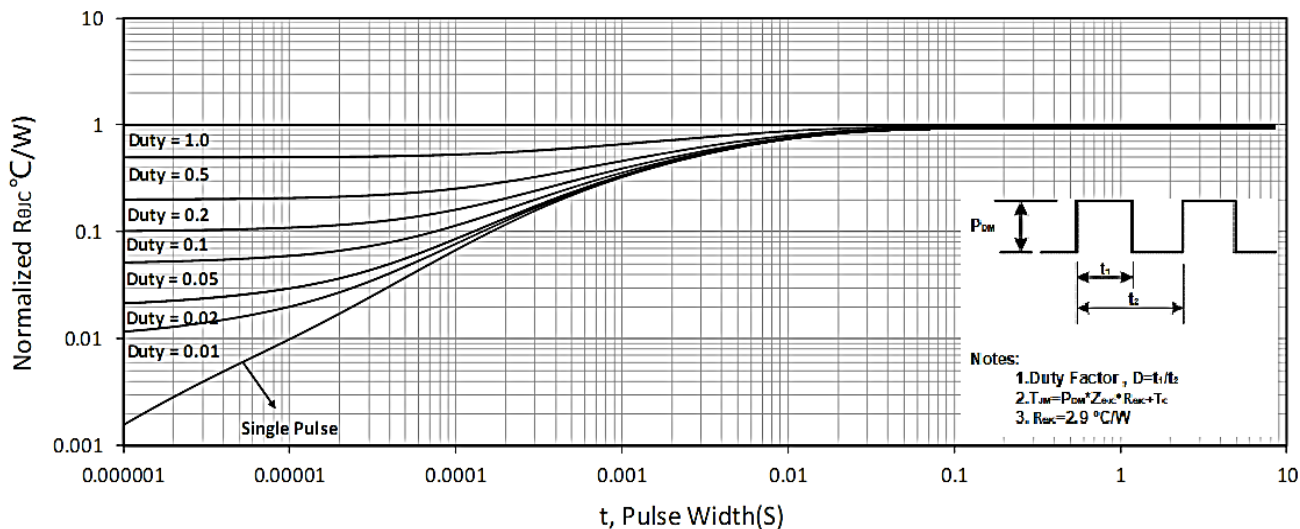
**Figure 8. Gate Charge Characteristics**



**Figure 9. Power Dissipation**

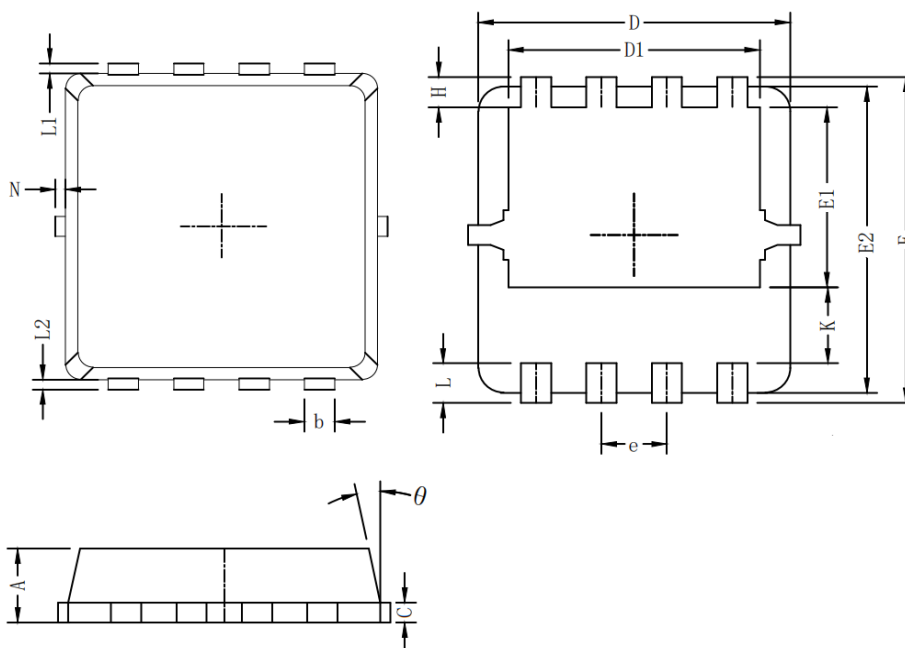


**Figure 10. Safe Operating Area**



**Figure 9 Normalized Maximum Transient Thermal Impedance**

Package Mechanical Data-PDFN3X3-8L



Symbol	Dim in mm		
	Min	Typ	Max
A	0.6	0.75	0.9
b	0.2	0.3	0.4
C	0.15	0.2	0.25
D	3	3.1	3.2
D1	2.3	2.45	2.6
E	3.15	3.3	3.45
E1	1.43	1.73	1.93
E2	2.9	3.05	3.2
e	0.65BSC		
H	0.2	0.35	0.5
K	0.57	0.77	0.87
L	0.3	0.4	0.5
L1/L2	0.1REF		
$\theta$	8°	10°	13°
N	0		0.15

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Edition	Date	Change
REV1.0	2023/3/31	Initial release

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